Abstracts

On-Wafer Calibration Techniques for Measurement of Microwave Circuits and Devices on Thin Substrates

J. Pla, W. Struble and F. Colomb. "On-Wafer Calibration Techniques for Measurement of Microwave Circuits and Devices on Thin Substrates." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1045-1048.

Two sets of on-wafer microstrip calibration standards were fabricated on 50 mu-m GaAs and 25 mu-m Polyimide substrates for the purpose of measuring microwave circuits and devices up to 50 GHz. The accuracies of one and two tier LRM and TRL calibration techniques were investigated on PHEMT devices. Substantial improvements were found with the use of a weight function in the averaging of two tier TRL and LRM-TRL calibrations. The dependence of the isolation on the spacing between the input and output probes was also determined for these thin substrates.

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